

<b>Notice of References Cited</b>	Application/Control No. 10/501,558		Applicant(s)/Patent Under Reexamination LUDVIKSSON, AUDUNN	
	Examiner Michael Maskell		Art Unit 2809	Page 1 of 1

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	M	US-			

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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